Stefano Bettarini

List of Publications by Year
in descending order

16	56	1937457 4	1588896 8
papers	citations	h-index	g-index

16	16	16	41
all docs	docs citations	times ranked	citing authors

#	Article	IF	Citations
1	Front-End Performance and Charge Collection Properties of Heavily Irradiated DNW MAPS. IEEE Transactions on Nuclear Science, 2010, 57, 1781-1789.	1.2	15
2	Characterization of Bulk Damage in CMOS MAPS With Deep N-Well Collecting Electrode. IEEE Transactions on Nuclear Science, 2012, 59, 900-908.	1.2	11
3	Performance evaluation of radiation sensors with internal signal amplification based on the BJT effect. Nuclear Instruments and Methods in Physics Research, Section A: Accelerators, Spectrometers, Detectors and Associated Equipment, 2006, 568, 217-223.	0.7	9
4	Modeling Charge Loss in CMOS MAPS Exposed to Non-Ionizing Radiation. IEEE Transactions on Nuclear Science, 2013, 60, 2574-2582.	1.2	7
5	Monolithic Pixel Sensors for Fast Silicon Vertex Trackers in a Quadruple Well CMOS Technology. IEEE Transactions on Nuclear Science, 2013, 60, 2343-2351.	1.2	4
6	Design and TCAD simulations of planar active-edge pixel sensors for future XFEL applications. , 2014, , .		4
7	Monolithic pixel sensors for fast particle trackers in a quadruple well CMOS technology. , 2012, , .		2
8	Effects of Substrate Thinning on the Properties of Quadruple Well CMOS MAPS. IEEE Transactions on Nuclear Science, 2014, 61, 1039-1046.	1.2	2
9	Nâ€“pâ€“n bipolar-junction-transistor detector with integrated pâ€“nâ€“p biasing transistorâ€”feasibility study, design and first experimental results. Semiconductor Science and Technology, 2006, 21, 194-200.	1.0	1
10	Quadruple Well CMOS MAPS With Time-Invariant Processor Exposed to Ionizing Radiation and Neutrons. IEEE Transactions on Nuclear Science, 2014, 61, 1763-1771.	1.2	1
11	Front-end performance and charge collection properties of heavily irradiated DNW MAPS. , 2009, , .		0
12	Characterization of bulk damage in CMOS MAPS with deep N-well collecting electrode. , 2011, , .		0
13	CMOS MAPS in a homogeneous 3D process for charged particle tracking. , 2012, , .		0
14	Quadruple well CMOS MAPS with time-invariant processor exposed to ionizing radiation and neutrons. , 2013, , .		0
15	Effects of substrate thinning on the properties of quadruple well CMOS MAPS. , 2013, , .		0
16	CMOS MAPS in a Homogeneous 3D Process for Charged Particle Tracking. IEEE Transactions on Nuclear Science, 2014, 61, 700-707.	1.2	0